

**Search Notes**

Application/Control No.

10/053,585

Examiner

Christopher L. Chin

Applicant(s)/Patent under  
Reexamination

NAYA ET AL.

Art Unit

1641

**SEARCHED**

Class	Subclass	Date	Examiner
updated	search	4/2/2007	CC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR